

A Complete Bibliography of Publications in *Technometrics* for the decade 1970–1979

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0.5 [Lad77]. 18 [Joh73a]. 2 [BN72]. 2^m [SC71]. 2^n [Joh79]. 2^{n-k} [Joh79]. 2×2 [MDM77]. 3 [Lin79]. 3^n [Hok74]. 4 [Dic74]. 5 [Dic74]. n [TW70]. A [Bad70, Bor72]. α [AS73, McC78a]. $A \subset B$ [Bad70, Bor72]. B [Bad70, Bor72]. β [AS73, GPU76]. C_P [Mal73, Ano73i, Ken71]. D [GK77a, Luc78, Mit74a, Mit74b, MB78a, MB78b, NGM70, SD75]. F [DW72, DW73, HH77, J.79u, Joh73b, Obe77, Pap72, PW72, HB71]. k [HP73, Ode71, WK71, Zei73]. $\log Y$ [Scl72]. m [FM77, HP73]. $m \leq 6$ [SC71]. N [Shu71, Gre70b, Sap73]. $n = 92$ [Wat70a]. O [MHL74]. p [Dun78a, FM77, For72, Lad77, MC72]. $P(Y < X)$ [KKS76]. $P[Y < X]$ [WK77]. $\Pr(Y < X)$ [Dow73]. $\Pr\{Y < X\}$ [JTS75, Ton74, Ton75]. R^2 [DH74]. s [Bha73, Lik74]. s^n [AT79]. σ^2 [JMM78]. t [AS73, KP79, Ros75c, SI70, TC72, YM74]. T^2 [BJN71]. T_M^2 [JH79]. V [SC71]. W [GH79, HH73, HL76, Ste78, Tho75]. X [Scl72]. Y [Scl72]. $|X'X|$ [Ano71a, Ano72e, Ano73h, BD71, Dyk71, Eva79].

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Matters [Ano72e, Ano73h, BD71]. **Maurice** [Fie73, Ger75]. **Maximize**
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McNeil [J.78d]. **Mead** [ON75]. **Mean**
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Meaning [Mal74, Mar74, BT74]. **Meaningful** [WW78]. **Means**
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Measurements [TB75]. **Measures** [WW78, Sne70]. **Measuring**
[Gru73b, HN70, Han75]. **Median** [Wol77b]. **Medical**
[Fle76, Lac72b, Ros75a]. **Meeting** [Ano70a]. **Meltzer** [Hel71b, Jac80]. **Men**
[Ens78]. **Mensing** [Gle77]. **Metagames** [Lut73]. **Meters** [Joi77]. **Method**

[All74, And70, And74, Ang74, Aro76, CR79, CBI79, GHW79, Gue77, Hoo79, J.76i, Lin79, OB76, SH79, See70, TW70, Yue78, ZNL79]. **Methoden** [JH73b]. **Methodology** [Dud79, Man73]. **Methods** [Bis72b, Boa79a, BCK61, Con74, Dav77, Dav79b, Dun72, Ehr77, FM71, Goo71, Gri70, HR75, J.76d, J.76e, J.77b, J.79q, J.79b, Jae70, Lac72b, Lan72, Leo70, MBC79, Mer79, Mih75, Mih77, NH72, Pat73, Ran70a, RH78, Sal75b, San72, Sne77, Sto76, Weg72, Zel72, BCK78, And75, Cor71, For71, Gib74, J.78i, J.78f]. **Meyer** [Joh71b]. **Michael** [Car77a, Sie75]. **Micro** [Car77b]. **Micro-Organisms** [Car77b]. **Microbiological** [Car77b]. **Microscale** [Ano73j, Mar73]. **MIL** [BS79, Koy78, Koy79]. **MIL-STD** [BS79]. **MIL-STD-105D** [Koy78, Koy79]. **Milestones** [CGO07]. **Milton** [K.71e]. **Minimal** [AT79]. **Minimization** [ON75]. **Minimizing** [For72]. **Minimum** [BD74, BR73, Dic74, Far75, Hal79, Nád71, NW77, NW79, Sch74a, SA79, Sch76, SLK79, SS78, Tho73, Vin76, WK77, HK77]. **Minimum-Point** [BD74]. **MINITAB** [J.78g]. **Misclassification** [Lac74b, Lac79, McL74a, Sor71, Sor72a, Sor72b, Sor73]. **Misclassified** [Lac74b, McL72, Ten72]. **Missing** [BDH70, HG73, Joh79, Pre71, Rub76, Wat70a]. **Misuse** [Kin79b]. **Mitra** [Ban73]. **MIVQUE** [SS78]. **Mixed** [Beh72, CR79, CS76, DS79, Haw72, HH73, SWD74]. **Mixing** [BR75, Cho79, Luk73]. **Mixture** [Ano76e, Beh70, BF72, Cha79, Cor75, CO75, Cor77, CK79, GK77b, Har79, Joh70c, Joh70b, MS74, Par78b, Ray72, Sch71a, Sne73, SM74, Sne75a, Sne75b]. **Mixtures** [Cor73, Cor79, DS77a, DS77b, Gri70, LC70, SN77, SM76, GK77a]. **Model** [Ano72g, Ano73j, Ant77, BDH70, Bri74, CF77, CS76, Cor77, DS77b, GLV74, Gue71b, HBA71, Hah72, HH73, HP71, Hil78, HJF78, HM73, Leo75, Man71a, Mar73, MW78, MHC77, MPB70, MA78, Nai74, OM72, Par78b, Pas79, Rah76, RR76, SWD70, SB72b, Tar76, TA75, TC73, WK71, WB74, WG78, Wio70, GDF78, J.75d]. **Model-Discrimination** [MPB70]. **Modeling** [LS71b, LSM72, PW77, Sch75]. **Modelling** [MPBD79, J.79m]. **Models** [Ano76e, BK70a, BG78, BL73, Cle71, DS77a, DAH73, Dun74, Fuc78, GK77b, Goo71, Gri79, GPS73, Har73a, Har73b, Hel74, HM77, K.71d, Lac74b, LR76, Lun75, MS74, MW73, Mer72, Par78a, Par78b, Pre75, PDB77, San72, San73, See73, SM74, Sne75b, Sne77, Spr76, Spr78, SWD74, TW72a, Wol78, Boa73, Boa79b, Hul73, J.75a, J.76g, Ron72, Smi77]. **Moderate** [Gut73b, MF77]. **Moderate-Size** [MF77]. **Modern** [Dun77b, Spr78]. **Modes** [Beh70]. **Modification** [Dav79a, Mie74, SOE75]. **Modifications** [Zah75b]. **Modified** [DM78, KM79, Koy78, Lin79, Luc73]. **Modular** [Bod70]. **Modulus** [SU79]. **Molenaar** [Hel71a]. **Moments** [Cha70b, Gro71b, Jae74]. **Monotone** [Sen74]. **Monotonicity** [Gro71b]. **Monte** [Rel70]. **Montgomery** [Dun77a]. **Moore** [Hub78]. **Morris** [Kin78, Ran70b, Win71]. **Morrison** [J.78e]. **Mortality** [MS73]. **Most** [Ala71, Bli72, EB77b]. **Mosteller** [Lac74a, Qua75, Odo77]. **MOSUMS** [BH78]. **Motion** [CF76, Nád73, PK76, Ser73, SS74]. **Motions** [HM73]. **Moving** [CK75, RH78, Ste72b, SWD74, Wic72]. **MR** [Kit81].

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 [Ait74, And74, Bea70, FH79, Goo71, Gor76, HG73, Haw72, LSYF79, SP74,
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 [K.71e, ON75]. **Nerlove** [Fre73a]. **Nested** [Ede74, GG70b, OL77, TA75].
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 [McC72, Mer77]. **Noise** [Shu71]. **Nomogram** [GW71]. **Non**
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 [Joi77]. **Noncentral** [MCL76, KP79]. **Noncentral-F** [MCL76]. **Nonlinear**
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Urn [Spr78]. **Use**

[Ano71f, Ano84, Bai74a, BH78, BMH76, CO75, Hub78, IC79, Kin79b, Kit79, LM72, NGM70, Nea70, PW72, Sne71, Sne75a, Woo73, Kit81]. **Used**

[Hoc72, JH73a, Leo70]. **Useful** [BK70b, Krz79, Whi70]. **Uses** [RTDM79].

Using [ABA72, AA74, Aus73, Bod70, BCK61, BR75, Cor77, Gre71, Har74, HH73, JB76, Kam72, KN74, Mar75, NW79, Pat76a, Rah76, Sin73, SLM74, TS79, WB74, Wig76, Zei73, BCK78, McC78a].

V [Bel70, Bis72b, Hac79, Hei78, Ing75, J.76b, J.79o, J.79u, Luc73, Sac75,

Sen75, Spr79, Wat73]. **V**. [HH73]. **Validation** [GHW79, Sne77]. **Validatory**

[Wol78]. **Validity** [Whe75]. **Value** [And75, Bai72, Bai73, Eas78, EB73, EB74, Eng75, EB77a, Has72, Law75a, Law78, MF73, MF77, NM78, TW72b].

Values [BK70b, BDH70, Dun71, Har74, HG73, JH79, Joh73b, MBC79, Pre71, Rub76, Sin72, You72a, Zah75b]. **Variable** [Ait74, All74, Bea70, BMP77,

Hun74, Kus79, Man70b, Man71d, McC75a, McK79]. **Variables**

[All71, BL71, BK70b, Cas76, Cha72, Fuc78, HH77, Har79, Hel74, LH70, MBC79, NW79, OIHS77, Sch70, SB72b, Tho73, Whe70, WY78, LH77].

Variance [BD72b, Bin74b, BD78, Bis79, BH74, BR73, CS76, CK79, Dav79b,

GG70b, GH79, GS71, Hal79, Hel74, HL76, JS76, Krz79, Low76, Man71a, MD71, McM71, MM73, MA78, Nai74, Rel70, Sal75b, Sch76, See70, SW72,

Sne76, SS78, TA71, WC70, WB75, Whe70, Wio70, WK77]. **Variances** [BD78, Bis79, Cha70b, Cor77, GG70a, HW75, Leo75, Low70, MN77, TJ79].

Variate [McD76]. **Variates** [AR73]. **Variation** [AR73, Ber72b, IM70, Zei73].

Variational [FM71]. **Varieties** [Joh78, Joh73a]. **Vasant** [Ing78b].
Vasudevan [Bri73a]. **Vaughn** [Woo75]. **Vector** [Nád70a]. **Vectors** [JH73a].
Verification [Lev79]. **Version** [Wes71]. **versus** [CM71, Cor77]. **Vertices**
[SM74]. **Via** [Mar76, Bin74a]. **Vick** [Bon76a]. **Viewed** [WB71]. **Viewpoint**
[WG78]. **Vincze** [J75e]. **Vinod** [HK77]. **Virginia** [Hei76]. **Visual**
[San72, San73]. **Vital** [Car77a]. **Vocabulary** [Dil71]. **Vol**
[J.75g, J.76h, J.78o]. **Volume** [Ano70o, Ano71l, Ano72l, Ano73p, Ano74l,
Ano75l, Ano76o, Ano77q, Ano78o, Ano78p, Ano79p, Bor72, Cra74, Fre73b,
Har72, J.77k, J.79q, J.79g, J.79f, K.71d, K.73b, K.73a, Lac71b, Sne74].
VOQL [Hal79]. **Vote** [Ano75m]. **vs** [LW71, MF75a, Scl72].

W [Add72, Add79, Ano74e, Bha72, Boy74, Dav70, Fre73a, Fre73c, Gle77,
GH75, Hay73, Hea78, Hel71a, Hub78, J.76d, J.76e, J.76a, J.77d, J.77f, J.77e,
J.77o, J.77q, J.77p, J.78n, J.78l, K.73d, Lac71b, Lac74a, Lan75, Law75b,
Leh71, Luk73, Mil72a, O'F73, Odo77, Qua74b, Qua74a, Sne76, Spr72].
Waiting [CM71, HD70]. **Waiting-Time** [HD70]. **Wald** [Sha79]. **Walpole**
[Fed74a, Dye74, Har77]. **Wani** [Gol74]. **Wasan** [Rog70a]. **Water**
[K.74a, Ven70]. **Watts** [Ano75f, Ran70c]. **Way**
[BG78, Dan78, GW75, HW75, HJ76, JD78, Kus79, Low76, MA78, Nai74].
Wayne [McC78b]. **Weak** [Ber72b]. **Weather** [Dav79a, Mie74, SOE75].

Weibull

[Ano73k, Ant77, Eas78, AJ77, Bai72, Bai73, BL74b, BAB72, Coh65, Coh73,
Coh75, D'A71a, D'A71b, Dan70, DA73, EB73, EB74, Eng75, EB75, EB77a,
EB78b, EB79, Fal70, Fin76, Gro71b, HBA71, KARR75, Law73, Law75a,
Law78, LL78, Lem75, Man70a, Man71b, Man72, MF73, MF75a, MF75b,
MF77, MHC77, MN77, NM78, Rou73, SS76, SA79, SW75, TBA70, TW72b].
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[Cor77, Har73b, Hin77a, JK71, NW79, Ste70, WC70]. **Weighting** [BH74].
Weights [GZ79]. **Weischedel** [Gor76]. **Welch** [Ros75c]. **Wetherill**
[Boa79a, Ehr77, Tsi78]. **Wheeler** [J.76b]. **Where** [Sar71]. **Whether** [Leo70].
Which

[Bri73b, BF74, Cha70b, DY70, Gru71b, Hoc72, Luc76, RSO72, Sta79, Ste72b].
White [Ano80b]. **Whitehouse** [Mar75]. **Whittemore** [J.79h]. **Wide**
[Tak72]. **Wilf** [J.79q]. **Wilkinson** [J.79m]. **Wilks** [Gra72]. **Willems** [Bak74].
William [Gle78, J.79k, Mil72a, Sal75a, Sam73, Woo74a]. **Williams**
[Dil71, J.77l, J.79a]. **Windowing** [Yue78]. **Winkler** [Hol73, Lac71b]. **Winn**
[Kin79b]. **Winsorized** [MHL77a, YF76]. **Wiorkowski** [Cro71]. **Within**
[BR79, J.76e, Sap73]. **Within-Group** [BR79]. **Within-Groups** [J.76e].
without [Gre71]. **Wolfe** [Ano78e, Gib74]. **Wolfowitz** [Sha79]. **Wolock**
[Ano74e]. **Wonnacott** [Bow78, Bow78]. **Wood** [Sne72a]. **Work** [Buc73].
Working [Ens78]. **Works** [CGO07]. **World** [Boa79a].

X [Sau73, Ury72]. **X-Ray** [Sau73].

Yates [Ber72a]. **Year** [Ens78, Ven70]. **Yonathan** [Cha75b]. **Youden** [DeG70]. **Yu** [Sen75]. **Yule** [Fie73, Fie73]. **Yvonne** [Odo77].
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